Listing of the Claims

- 1. (Currently Amended) A monitoring system for dark-field imaging of a target area below a surface of an object, the monitoring system including
 - an illumination optical system (31) to emit an illumination beam along an illumination beam path onto the object and
 - an imaging system (35) to receive a returning imaging beam from the target area along an imaging beam path, wherein
 - the imaging system includes a selective optical interception system (32,37,51,52) to intercept a returning illumination beam from the region between the surface and the target area.
- 2. (Original) A monitoring system as claimed in Claim 1, wherein
 - the illumination system is arranged to produce the illumination beam as a polarised illumination beam and
 - the selective optical interception system includes a polarisation-analyser having its axis crossed relative to the polarisation axis of the polarised illumination beam.
- 3. (Original) A monitoring system as claimed in Claim 1, wherein the selective optical interception system includes an aperture stop that essentially intercepts a central portion of the returning imaging beam.
- 4. (Original) A monitoring system for dark-field imaging of a target area below a surface of an object, the monitoring system including
 - an illumination optical system to emit an illumination beam along an illumination beam path onto the object and
 - an imaging system to receive a returning imaging beam from the target area along an imaging beam path, wherein
 - the illumination optical system produces an unfocussed illumination beam.

- 5. (Original) A monitoring system for dark-field imaging of a target area below a surface of an object, the monitoring system including
 - an illumination optical system to emit an illumination beam along an illumination beam path onto the object and
 - an imaging system to receive a returning imaging beam from the target area along an imaging beam path, wherein
 - the illumination beam path and the imaging beam path subtend an angle and
 - the illumination optical system has an illumination focus,
 - the imaging system has an imaging focus and
 - the illumination focus being displaced from the imaging focus.
- 6. (Currently Amended) An analysis apparatus comprising
 - a spectroscopy system that includes
 - an excitation system (1)-to emit an excitation beam to a target area below a surface of an object and
 - the analysis apparatus further comprising a monitoring system (31,35) to image the target area, the monitoring system including
 - a illumination optical system (31)-to emit an illumination beam along an illumination beam path onto the object and
 - an imaging system (35) to receive a returning imaging beam from the target area along an imaging beam path, wherein
 - the illumination beam path and the imaging beam path subtend an angle.
- 7. (Currently Amended) An analysis apparatus comprising a spectroscopy system that includes
 - an excitation system to emit an excitation beam to a target area below a surface of an object and

the analysis apparatus further comprising a monitoring system as claimed in any one of Claims 1 to 5.